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| Notice of References Cited | Application/Control No. 10/539,194 | Applicant(s)/Patent Under Reexamination KERR ET AL. | |
| | Examiner Huy C. Ho | Art Unit 2617 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------------------|----------------|
| * | A | US-7,181,202 | 02-2007 | Rasanen et al. | 455/418 |
| * | B | US-6,032,043 | 02-2000 | Houde, Michel | 455/433 |
| * | C | US-6,131,026 | 10-2000 | Badillo, Eduardo Teodoro Sanchez | 455/428 |
| * | D | US-6,987,974 | 01-2006 | Mostafa et al. | 455/455 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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